

N-Channel 25 V (D-S) MOSFET with Schottky Diode



PRODUCT SUMMARY					
MOSFET					
V _{DS} (V)	25				
$R_{DS(on)}$ max. (Ω) at $V_{GS} = 10 \text{ V}$	0.00096				
$R_{DS(on)}$ max. (Ω) at $V_{GS} = 4.5 \text{ V}$	0.00140				
Q _g typ. (nC)	31.5				
I _D (A) a, g	60				
SCHOTTKY					
V _F (V) at 10 A	0.55				
I _F (A) ^{a, g}	60				
Configuration	Single plus integrated Schottky				

FEATURES

- TrenchFET® Gen IV power MOSFET
- SKYFET® with monolithic Schottky diode

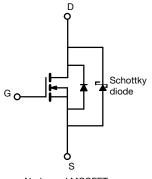




- 100 % R_a and UIS tested
- Material categorization: for definitions of compliance please see <u>www.vishay.com/doc?99912</u>

APPLICATIONS

- · Synchronous buck
- Synchronous rectification
- DC/DC conversion



N-channel MOSFET

ORDERING INFORMATION	
Package	PowerPAK SO-8
Lead (Pb)-free and halogen-free	SiRC16DP-T1-GE3

PARAMETER	SYMBOL	LIMIT	UNIT			
Drain-source voltage		V _{DS}	25	V		
Gate-source voltage		V _{GS}	+20, -16	V		
Continuous drain current (T _J = 150 °C)	T _C = 25 °C		60 ^a			
	T _C = 70 °C		60 ^a			
	T _A = 25 °C	I _D	57 b, c			
	T _A = 70 °C		45 b, c			
Pulsed drain current (t = 100 µs)		I _{DM}	250	A		
Continuous source current (MOSFET diode conduction)	T _C = 25 °C		60 ^a			
	T _A = 25 °C	I _S	5 a, b			
Single pulse avalanche current	. 0.1!!	I _{AS}	30			
Single pulse avalanche energy	L = 0.1 mH	E _{AS}	45	mJ		
Maximum power dissipation	T _C = 25 °C		54.3			
	T _C = 70 °C		34.7	w		
	T _A = 25 °C	P _D	5 b, c			
	T _A = 70 °C		3.2 b, c			
Operating junction and storage temperature range		T _J , T _{stq}	-55 to +150			
Soldering recommendations (peak temperature)		3	260	°C		



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THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum junction-to-ambient b, f	t ≤ 10 s	R_{thJA}	20	25	°C/W	
Maximum junction-to-case (drain)	Steady state	R_{thJC}	1.8	2.3	G/ VV	

Notes

- a. Package limited
- b. Surface mounted on 1" x 1" FR4 board
- c. t = 10 s
- d. See solder profile (www.vishay.com/doc?73257). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components
- f. Maximum under steady state conditions is 65 °C/W
- g. $T_C = 25 \,^{\circ}C$

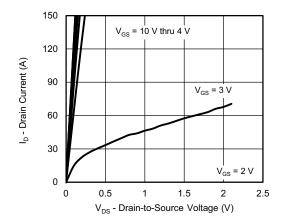
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-source breakdown voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	25	-	- 1	.,	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	-	2.4	V	
Gate-source leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = +20 V, -16 V	-	-	± 100	nA	
		$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}$	-	0.06	0.10	0 .	
Zero gate voltage drain current	I _{DSS}	V _{DS} = 25 V, V _{GS} = 0 V, T _J = 70 °C	-	1	10	mA	
On-state drain current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	40	-	-	Α	
D	` ′	V _{GS} = 10 V, I _D = 15 A	-	0.00080	0.00096		
Drain-source on-state resistance a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 10 A	-	0.00110	0.00140	Ω	
Forward transconductance a	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 15 \text{ A}$	-	67	-	S	
Dynamic ^b		- -					
Input capacitance	C _{iss}		-	5150	-	pF	
Output capacitance	C _{oss}		-	1950	-		
Reverse transfer capacitance	C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	350	-		
C _{rss} /C _{iss} ratio			-	0.068	0.140		
Talal and a share a		$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	69	105	nC	
Total gate charge	Qg	V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 10 A	-	31.5	48		
Gate-source charge	Q _{gs}		-	12.1	-		
Gate-drain charge	Q_{gd}		-	5.6	-		
Gate resistance	R_g	f = 1 MHz	0.1	0.5	0.9	Ω	
Turn-on delay time	t _{d(on)}		-	13	26		
Rise time	t _r	V_{DD} = 10 V, R_L = 1 Ω , $I_D \cong$ 10 A, V_{GEN} = 10 V, R_g = 1 Ω	-	21	42	1	
Turn-off delay time	t _{d(off)}		-	35	70		
Fall time	t _f		-	9	18	no	
Turn-on delay time	t _{d(on)}		-	26	52	ns	
Rise time	t _r	$\begin{split} V_{DD} = 10 \text{ V}, \text{ R}_L = 1 \Omega, \text{ I}_D &\cong 10 \text{ A}, \\ V_{GEN} = 4.5 \text{ V}, \text{ R}_g = 1 \Omega \end{split}$	-	36	72		
Turn-off delay time	t _{d(off)}		ı	31	62		
Fall time	t _f		-	12	24		
Drain-source Body Diode Characteristi	cs						
Continuous source-drain diode current	I _S	T _C = 25°C -		-	60	Α	
Pulse diode forward current	I _{SM}			-	100		
Body diode voltage	V _{SD}	$I_S = 5 \text{ A}, V_{GS} = 0 \text{ V}$	-	0.41	0.55	V	
Body diode reverse recovery time	t _{rr}		-	46	92	ns	
Body diode reverse recovery charge	Q _{rr}	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	47	94	nC	
Reverse recovery fall time	t _a	$T_J = 25 ^{\circ}C$	-	21	-		
Reverse recovery rise time	t _b		-	25	_	ns	

Notes

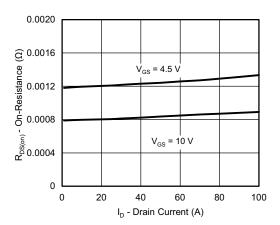
- a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %
- b. Guaranteed by design, not subject to production testing

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

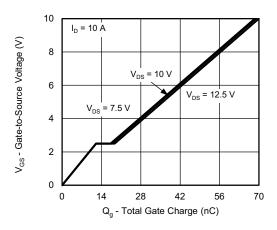




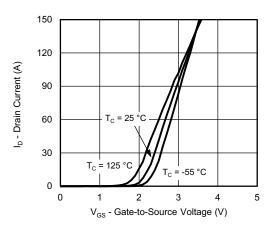
Output Characteristics



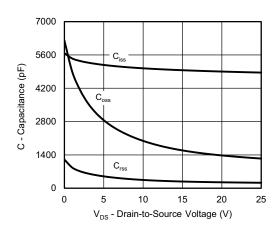
On-Resistance vs. Drain Current and Gate



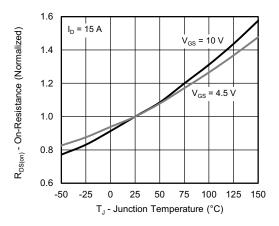
Gate Charge



Transfer Characteristics

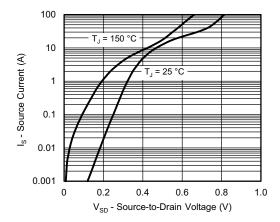


Capacitance

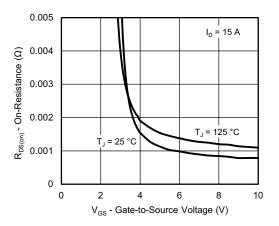


On-Resistance vs. Junction Temperature

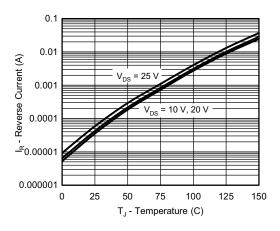




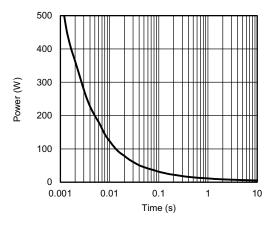
Source-Drain Diode Forward Voltage



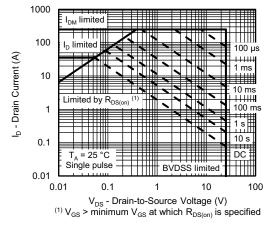
On-Resistance vs. Gate-to-Source Voltage



Reverse Current vs. Junction Temperature

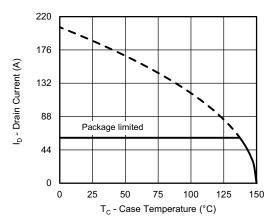


Single Pulse Power

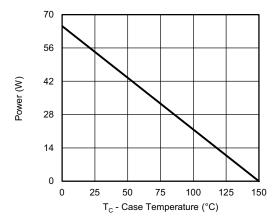


Safe Operating Area, Junction-to-Ambient

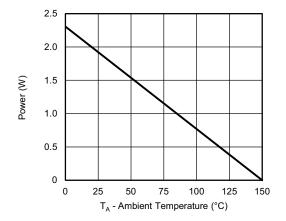




Current Derating a





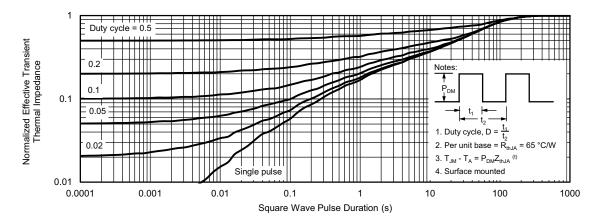


Power, Junction-to-Ambient

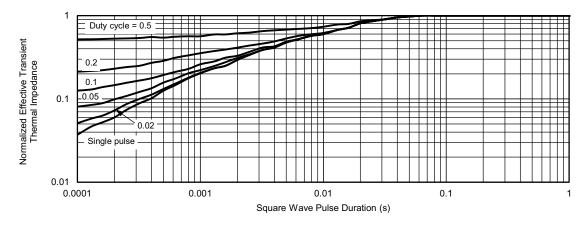
Note

a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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